

ABSTRACT OF THE DISCLOSURE

The integrated circuit test system and method prevent the occurrence of frost under a very low temperature environment during the exchange of integrated circuits under environmental testing and allows for the continuous testing thereof. The integrated circuit test system comprises a test chamber, a portion of which is adapted to interface with a tester having a circuit panel. An auxiliary chamber is adjacent the test chamber, the auxiliary chamber including a first door between the auxiliary chamber and the test chamber, the auxiliary chamber further including a second door between the auxiliary chamber and an external region, the auxiliary chamber for receiving a sample prior to and following a test. A transfer unit is also in the chamber, for transferring the sample between the test chamber and the auxiliary chamber through the first door. Accordingly, the time consumed during the exchange of testing samples is shortened. In addition the sample and respective test system components are prevented from being damaged by maintaining a low moisture environment.

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